

ABSTRACT

Methods are described for analyzing at least one deformable object (O) in a suspension fluid, including the following steps: generation of an electric positioning field and positioning of the object (O) in a potential minimum of the positioning field, generation of an electric deformation field in such a way that a deformation force is exerted on the object (O), and detection of at least one property selected from the group including the dielectric, geometric and optical properties of the object (O), wherein the positioning field is generated in a compartment (12) of a fluidic microsystem (10) and the positioning of the object (O) takes place in a contactless manner in a freely suspended state. Measuring apparatuses for carrying out this method are also described.